

Notice of References Cited

Application/Control No.

09/888,015

Applicant(s)/Patent Under
Reexamination
BRETON ET AL.

Examiner

Todd D Ware

Art Unit

1615

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4.466.961	08-1984	Szijjarto nee Auber et al	424/18088/01166
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	P	JP 63030403	02-1988	JPO	Ekoshi	
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